



Beam Diagnostics Lecture 2

Measuring Complex Accelerator Parameters Uli Raich CERN AB-BI

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Contents of lecture 2



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- Some examples of measurements done with the instruments explained during the last lecture
 - Spectroscopy
 - Trajectory and Orbit measurements
 - Tune measurements
 - Traditional method
 - BBQ method
 - Transverse and longitudinal emittance measurements
 - Longitudinal phase space tomography



Faraday Cup application Testing the decelerating RFQ



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Antiproton decelerator

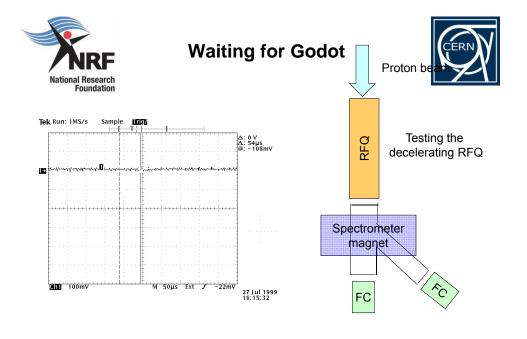
- Accelerate protons to 24 GeV and eject them onto a target
- Produce antiprotons at 2 GeV
- Collect the antiprotons and cool them
- Decelerate them and cool them
- Output energy: 100 MeV

In order to get even lower energies:

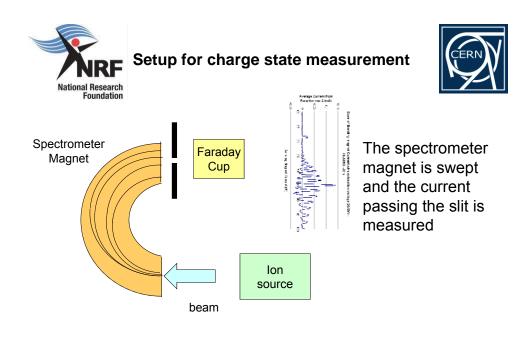
- Pass them through a moderator
 - High losses
 - · Large energy distribution

=> Build a decelerating RFQ

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Measuring charge state distribution National Research Foundation Faraday Cup Slit Spectrometer magnets 6

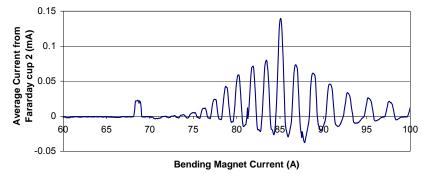
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Charge state distribution measured with a Faraday Cup on a heavy ion source



Scan of Bending magnet Current with extraction voltage 20.5kV -11/04/03 -JCh



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Trajectory and Orbit measurements



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Definitions:

Trajectory: Orbit: The mean positions of the beam during 1 turn The mean positions over many turns for each of the BPMs

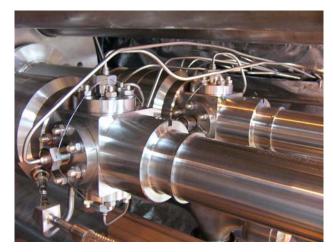
The trajectories must be controlled at injection, ejection, transition Closed orbits may change during acceleration or RF "gymnastics"



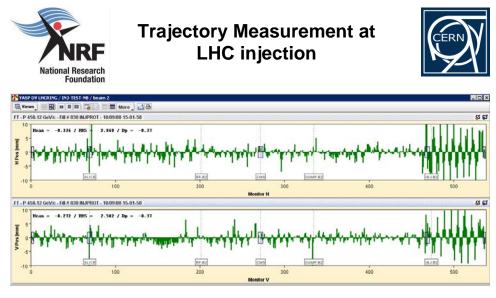
LHC Button BPMs



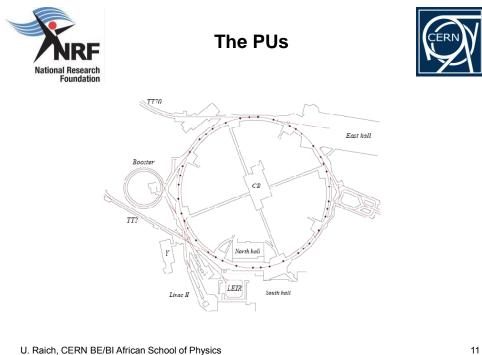
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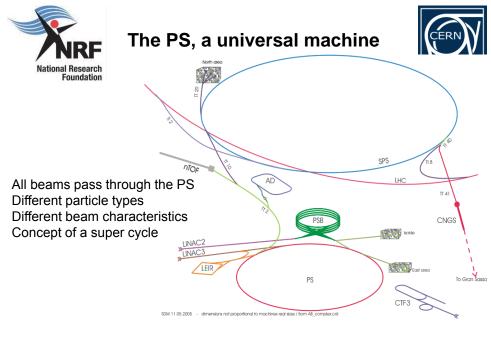


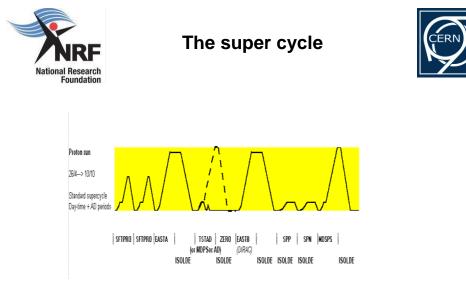
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Knowing the optics one can deduce the orbit correction from the measurement







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Position Measurements



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Red: The sum signal Green: The difference signal

Procedure:

 Produce integration gates and
 100

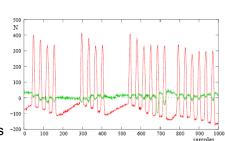
 Baseline signals
 0

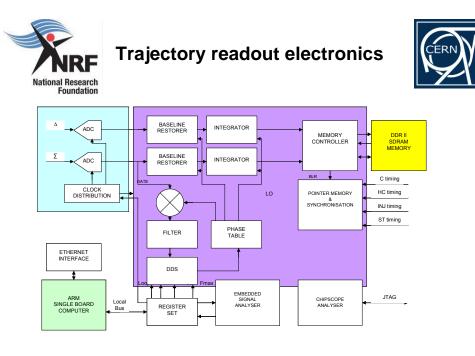
 Baseline correct both signals
 -100

 Integrate sum and difference signals
 -200

 and store results in memory
 Take external timing events into

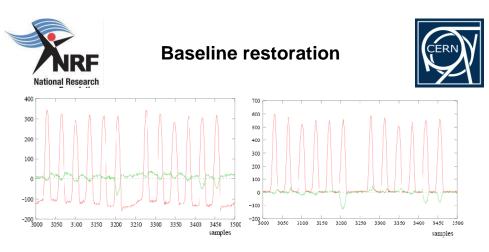
 account e.g. harmonic number
 change, γ-transition etc.



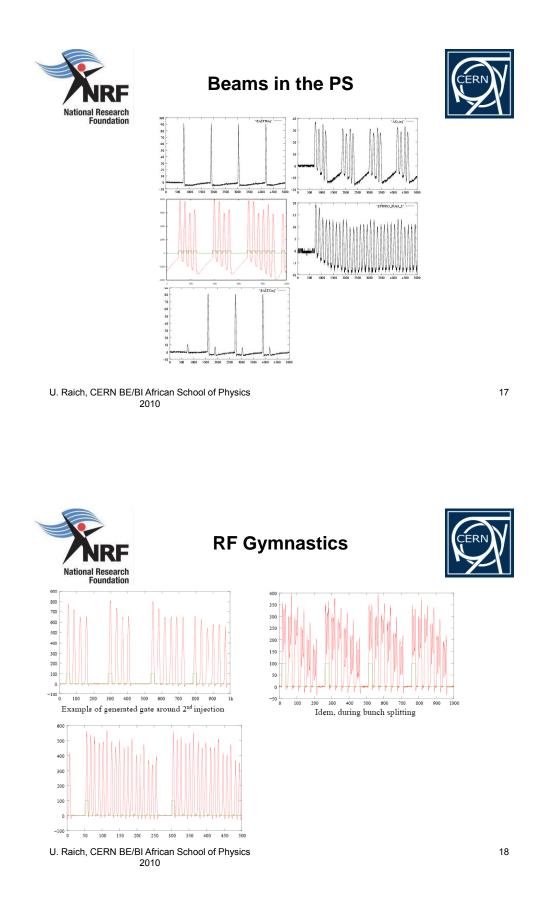


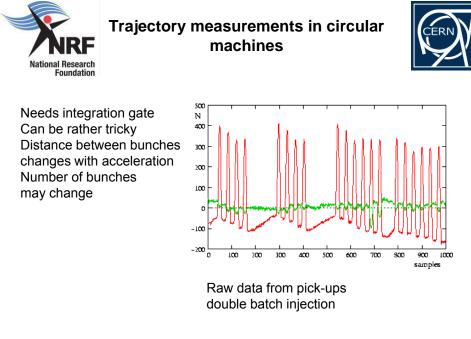
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Low pass filter the signal to get an estimate of the base line Add this to the original signal





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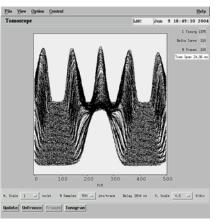


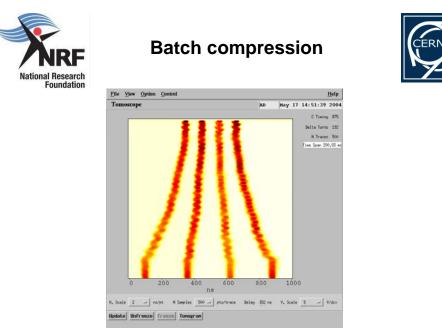
Changing bunch frequency



- Bunch splitting or recombination
- One RF frequency is gradually decrease while the other one is increased
- Batch compression

For all these cases the gate generator must be synchronized







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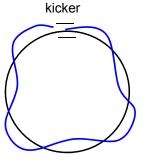
• When the beam is displaced (e.g. at injection or with a deliberate kick, it starts to oscillate around its nominal orbit (betatron oscillations)

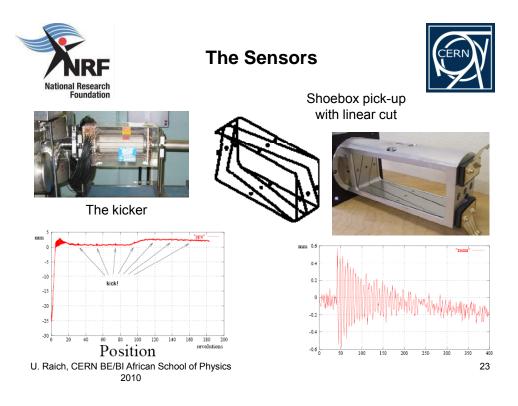
Tune measurements

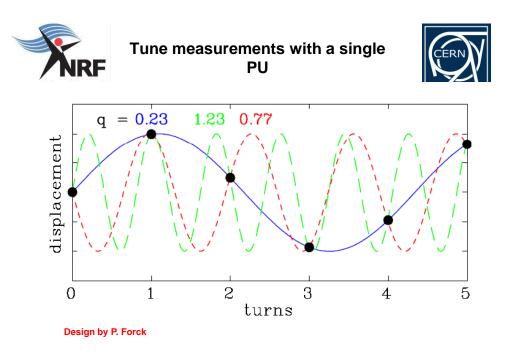
- Measure the trajectory
- Fit a sine curve to it

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• Follow it during one revolution







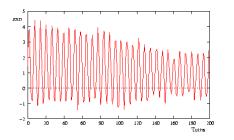
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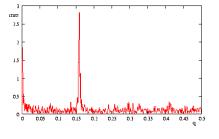


Kicker + 1 pick-up



- · Measures only non-integral part of Q
- Measure a beam position at each revolution

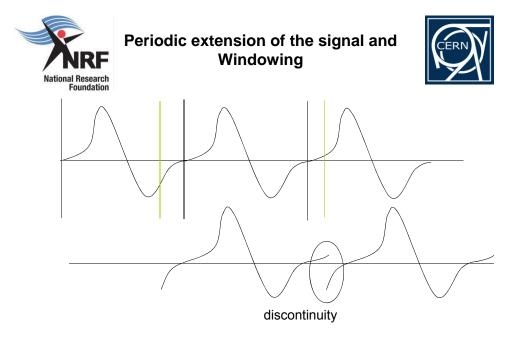




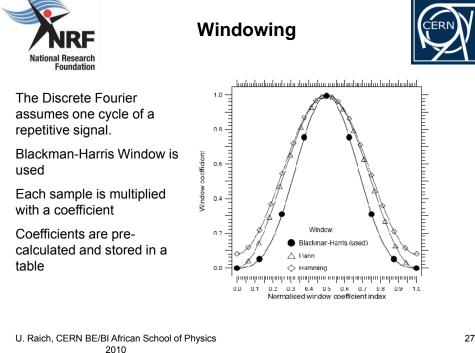
Fourier transform of pick-up signal

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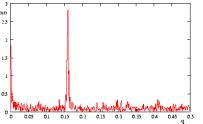


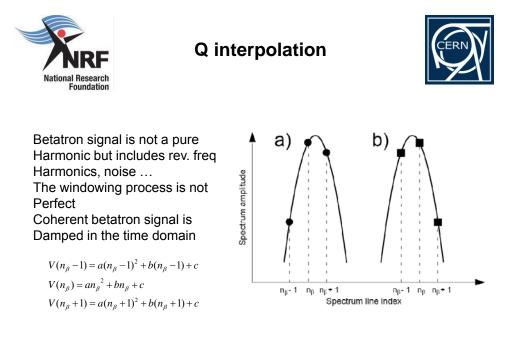


Peak search algorithm



- Power value is bigger than its predecessor
- Power value is bigger than its successor
- Power value is biggest in the whole spectrum ٠
- The power value is at least 3 times bigger than the arithmetic ٠ mean of all power bins.





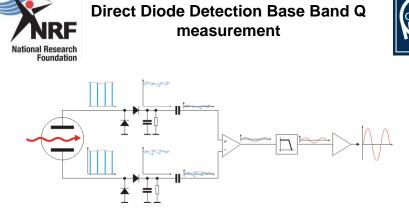
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Q-Measurement Results



	Control	_	_	_				-	_		_		N meas	
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N meas	:	55	Inte	rval	[ms]:	10	c st	lart	[ns]	1	270			4
Kick H	:	Cn	Kick	v	:	On	Fin	Ţ		1	3		Interval [ms]	. :
Gain H	:	200	Gair.	V	:	200	Zetu	uatio	n	:	0n		C Chant [ma]	2
Fractional q values												C Start [ms]	2 7	
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	N											ľ		
0.40	1												Gain H	: 2
0.40		••••	••••				•,••	••••	****		1			2 2
r	***		••••	••••			••••	••••	 -					. 2
r					•••••	600	••••	••••	6 44 6 49	, , , - -	802		Gain V	. 2



Diode Detectors convert spikes to saw-tooth waveform

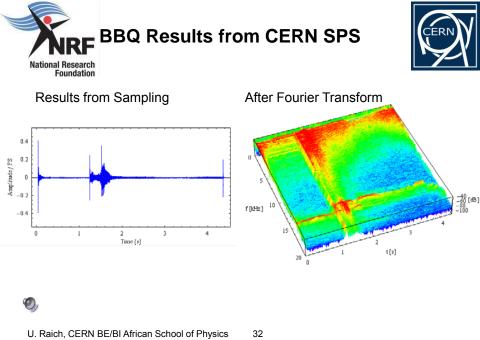
Signal is connected to differential amplifier to cut out DC level

Filter eliminates most of the revolution frequency content

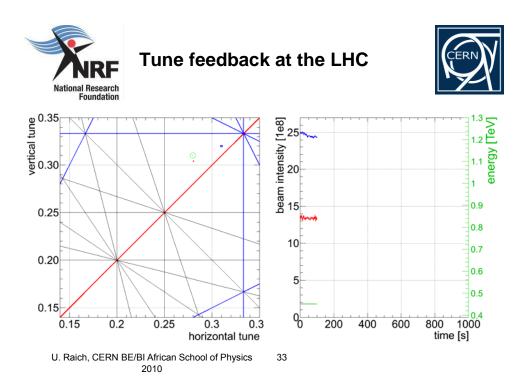
Output amplifier brings the signal level to amplitudes suitable for long distance transmission

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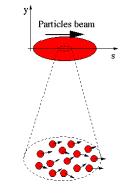
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Emittance measurements



A beam is made of many many particles, each one of these particles is moving with a given velocity. Most of the velocity vector of a single particle is parallel to the direction of the beam as a whole (s). There is however a smaller component of the particles velocity which is perpendicular to it (x or y).

$$\vec{v}_{particle} = v_s \hat{u}_s + v_x \hat{u}_x + v_y \hat{u}_y$$

Design by E. Bravin

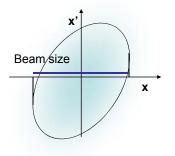
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Emittance measurements



- If for each beam particle we plot its position and its transverse angle we get a particle distribution who's boundary is an usually ellipse.
- The projection onto the x axis is the beam size



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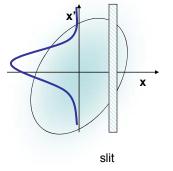
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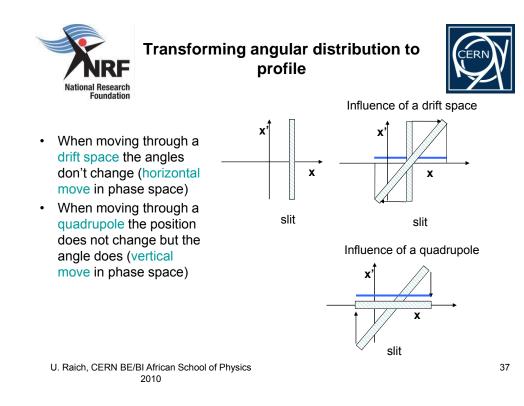
The slit method



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- If we place a slit into the beam we cut out a small vertical slice of phase space
- Converting the angles into position through a drift space allows to reconstruct the angular distribution at the position defined by the slit





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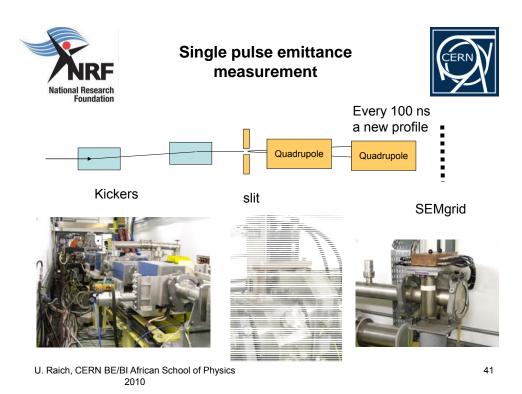


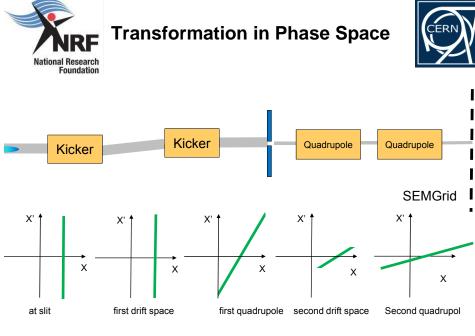


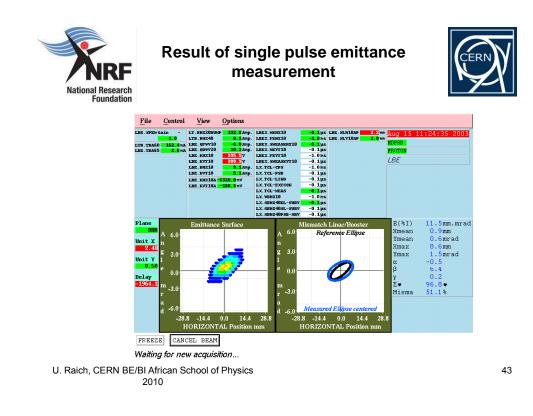
Moving slit emittance measurement



- · Position resolution given by slit size and displacement
- Angle resolution depends on resolution of profile measurement device and drift distance
- High position resolution \rightarrow many slit positions \rightarrow slow
- · Shot to shot differences result in measurement errors









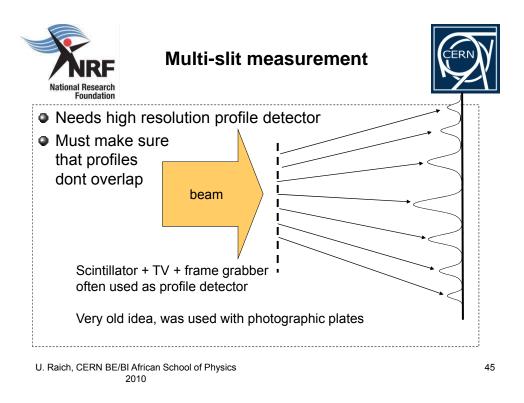
Single Shot Emittance Measurement



Advantage:

- Full scan takes 20 µs
- Shot by shot comparison possible
- Disadvantage:
 - Very costly
 - Needs dedicated measurement line
 - Needs a fast sampling ADC + memory for each wire
- Cheaper alternative:
 - Multi-slit measurement

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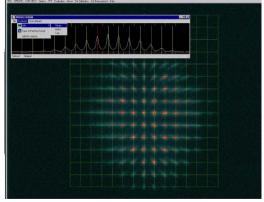




Pepperpot



Uses small holes instead of slits Measures horizontal and vertical emittance in a single shot



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Photo P. Forck

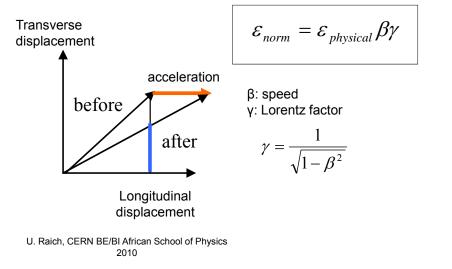


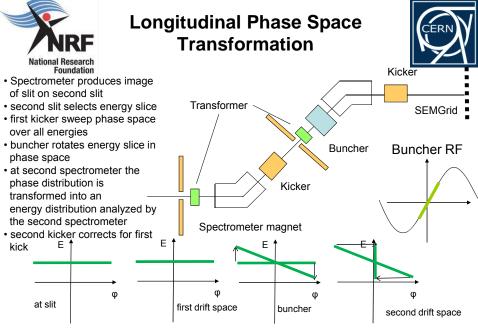
Adiabatic damping



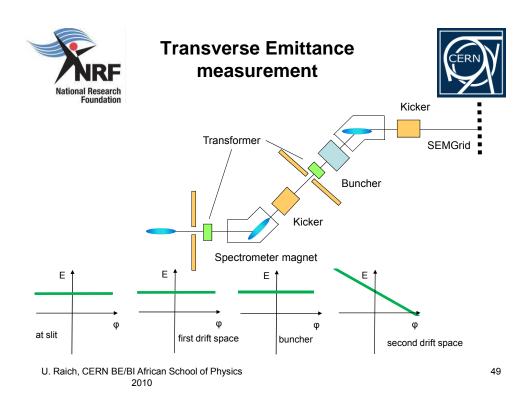
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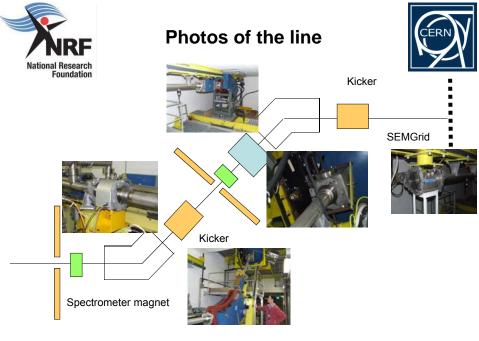
Change of emittance with acceleration

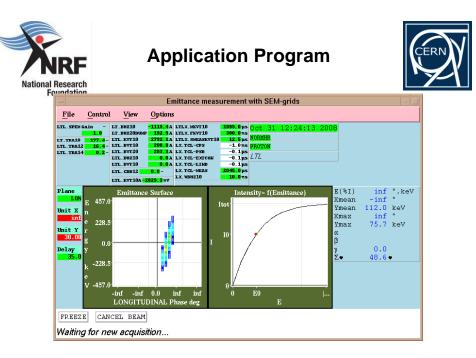




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Computed Tomography (CT)

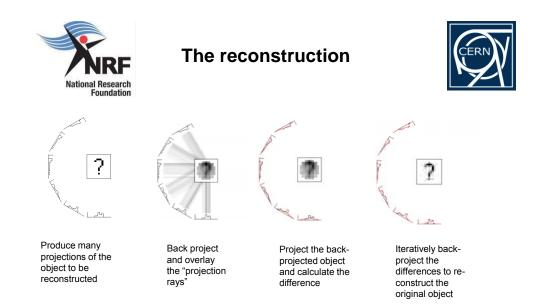


Principle of Tomography:

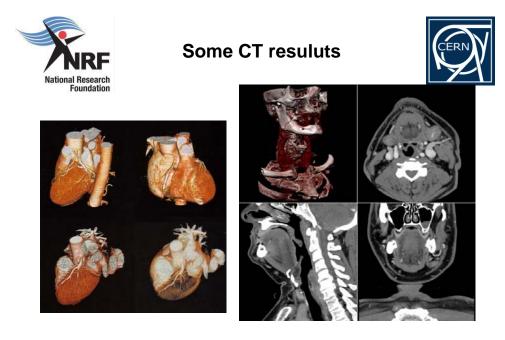
• Take many 2-dimensional Images at different angles

• Reconstruct a 3-dimensional picture using mathematical techniques (Algebraic Reconstruction Technique, ART)





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Computed Tomography and Accelerators

eEz

Φs

eE_o cosΦ_S

Ð

separatrix

0s



RF voltage

Restoring force for nonsynchronous particle

Longitudinal phase space

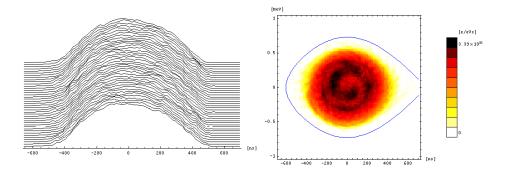
Projection onto Φ axis corresponds to bunch profile

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